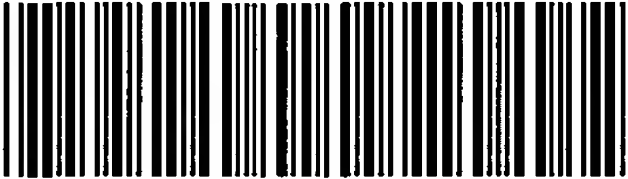


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/644,756	TAGAWA ET AL.	
	Examiner	Art Unit	
	Laura A. Grier	700	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
700	94	5/13/2005	LAG
369	30.04	5/13/2005	LAG

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventorship Search	5/13/2005	LAG
Consulted Xu Mei	5/17/2005	LAG